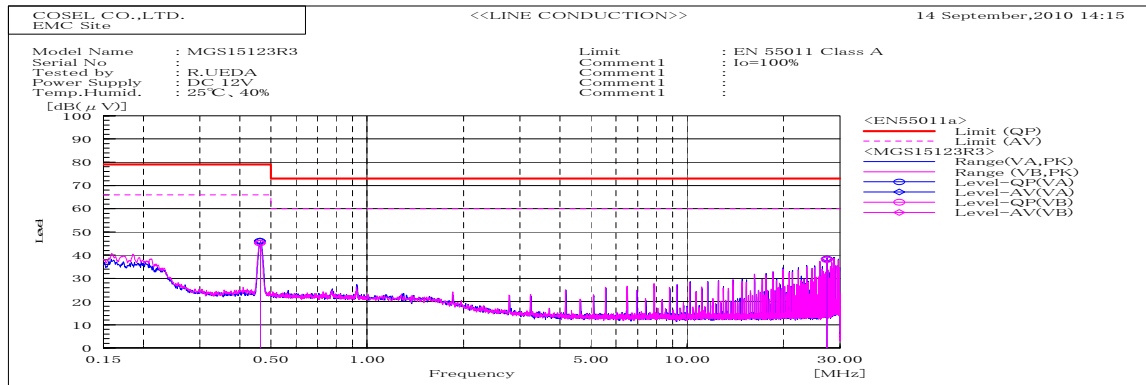
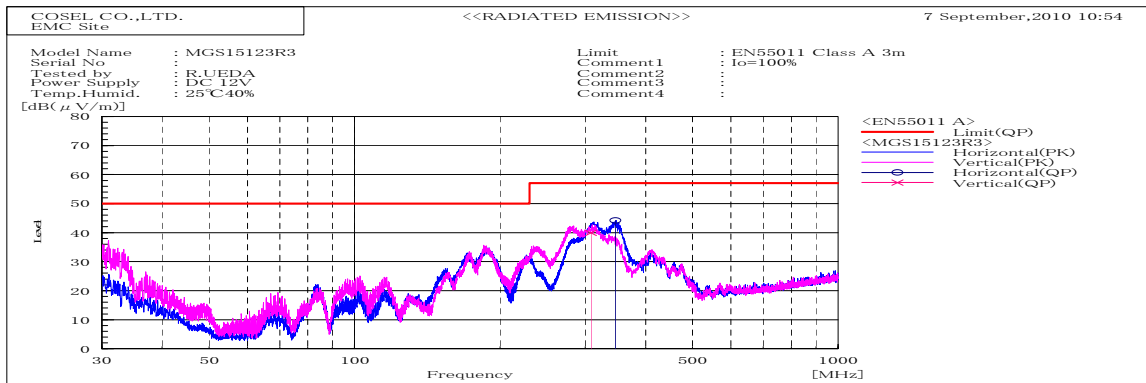


DATA SHEET		Date	21-Sep-10
Model	MGS15123R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46227		VB	35.2	35.3	10	45.2	45.3	79	66	33.8	20.7	Pass	
0.46256		VA	35.9	36	10.1	46	46.1	79	66	33	19.9	Pass	
27.3044		VB	27	27.4	11	38	38.4	73	60	35	21.6	Pass	
27.30355		VA	27.6	27.7	10.7	38.3	38.4	73	60	34.7	21.6	Pass	

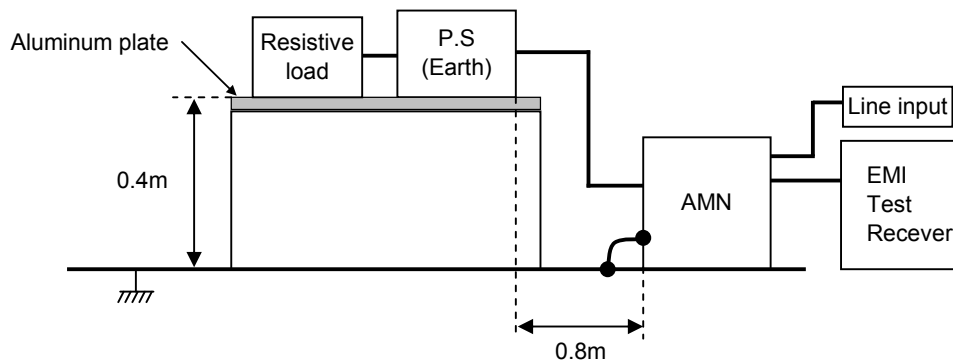


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
308.176	V	Stable	57.3	-17.4		39.9		57	17.1	Pass	128	72	
346.305	H	Stable	60.6	-16.4		44.2		57	12.8	Pass	110	27	

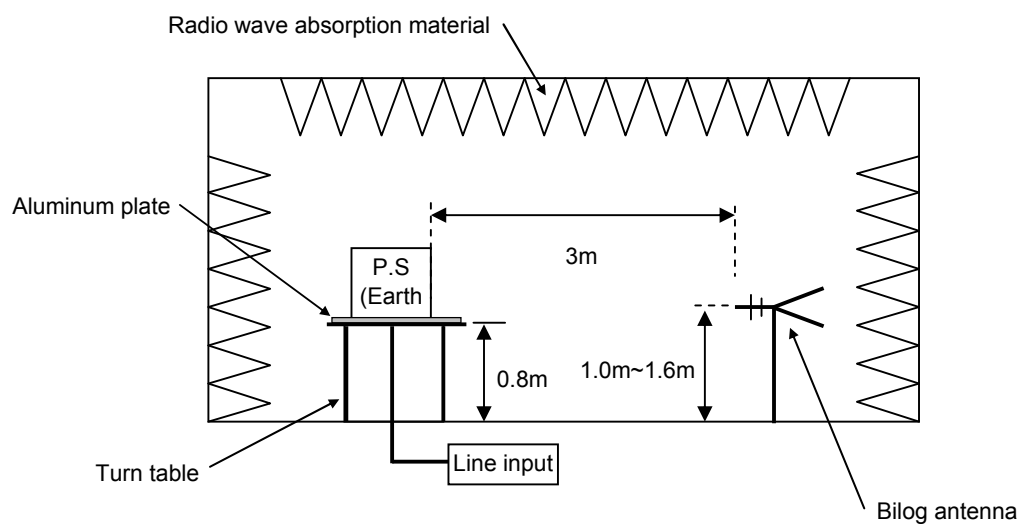
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

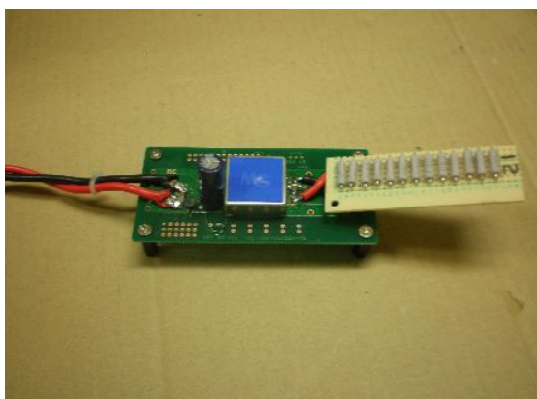


Conditions

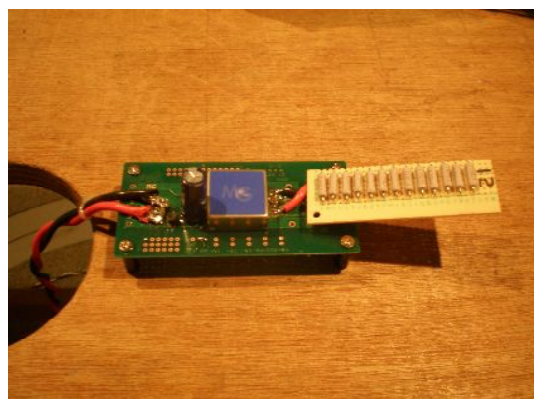
Test : EMI
Model Name : MGS1512□□/MGW1512□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

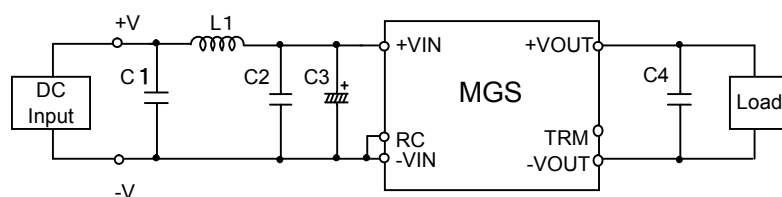


Fig.1 Testing circuitry 1

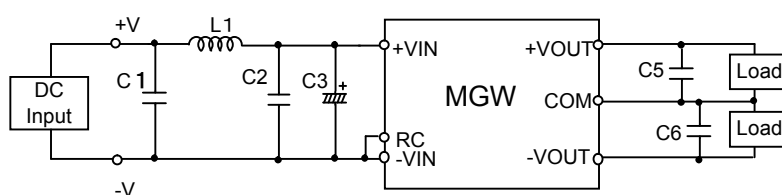


Fig.2 Testing circuitry 2

L1	:	0.5 μ H	CI4C-0R5	(KORIN ELECTRONICS)
C1,C2	:	25V 10 μ F	CM316X5R106K25A	(KYOCERA)
C3	:	50V 220 μ F	LXY50VB220M	(NIPPON CHEMI-CON)
C4,C5,C6	:	25V 22 μ F	CM32X5R226K25A	(KYOCERA)